



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:
Barber et al.

) Docket No.: 20.2895

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) Group Art Unit:

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) Confirmation:

)

) Examiner:

)

Serial No.: 10/707,813

Filed: January 14, 2004

For: Apparatus and Methods for Determining Isotropic and
Anisotropic Formation Resistivity in the Presence of Invasion

CERTIFICATE OF MAILING	
I hereby certify that this correspondence (along with any document referenced as being attached or enclosed hereto) is being deposited with the United States Postal Service in an envelope as First Class Mail addressed to: Commissioner for Patents, PO Box 1450, Alexandria VA 22313-1450 on this date by the person signing below.	
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INFORMATION DISCLOSURE STATEMENT

Dear Sir:

The following documents on the Form PTO-1449 are submitted to the United States Patent and Trademark Office under provisions of 37 CFR 1.97-1.98. A copy of each reference is enclosed.

Please charge any necessary fees to the deposit account for Schlumberger Technology Corporation,
Account No. 19-0610.

Respectfully Submitted,

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Registration Number 46,258

Date: J - 16, 2004

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FORM PTO-1449 (Modified)

ATTY. DOCKET NO.
20.2895SERIAL NO.
10/707,813LIST OF INFORMATION PROVIDED
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(Use several sheets if necessary)

APPLICANT: Barber et al.

FILING DATE:
January 14, 2004

GROUP

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Patentee
AA			
AB			
AC			
AD			
AE			
AF			
AG			
AH			
AI			

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Translation Yes No
AJ				
AM				
AN				
AO				

OTHER INFORMATION PROVIDED (AUTHOR, TITLE, DATE, PLACE OF PUBLICATION, PERTINENT PAGES, ETC.)

AR	Hunka et al., "A New Resistivity Measurement System for Deep Formation Imaging and High-Resolution Formation Evaluation," SPE 20559, 65 th Annual Technical Conference and Exhibition, New Orleans LA, September 23-26, 1990 (pp. 295-307)
AS	Moran et al., "Effects of Formation Anisotropy on Resistivity-Logging Measurements," Geophysics, Vol. 44, NO. 7 (July 1979) pp. 1266 - 1286
AT	Anderson et al., "The Response of Induction Tools to Dipping, Anisotropic Formations," SPWLA 36 th Annual Logging Symposium, June 26 - 29, 1995, Paper D

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

1. The attached cited information should not be construed as an admission that any of the above items are prior art to the subject invention.

2. This is not a representation that a search has been made.

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REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

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BA			
BB			
BC			
BD			
BE			
BF			
BG			
BH			
BI			

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Translation Yes	No
BL					
BM					
BN					
BO					

OTHER INFORMATION PROVIDED (AUTHOR, TITLE, DATE, PLACE OF PUBLICATION, PERTINENT PAGES, ETC.)

BR	Anderson et al., "The Effect of Crossbedding Anisotropy on Induction Tool Response," SPWLA 39 th Annual Logging Symposium, May 26-29, 1998, Keystone, CO, Paper B
BS	Davydycheva et al., "An Efficient Finite-Difference Scheme for Electromagnetic Logging in 3D Anisotropic Inhomogeneous Media," Geophysics Vo. 68, No. 5 (September - October 2003) pp. 1525-1536.
BT	

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